


<b>Search Notes</b>  	<b>Application/Control No.</b>  10585750	<b>Applicant(s)/Patent Under Reexamination</b>  NOGUCHI ET AL.
	<b>Examiner</b>  Pablo N Tran	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	557,, 556.1, 575.6,, 90.3, 550.1, 558, 575.1, 556.2, 90.2, 73, 344	3/29/09	Pt
379	419, 433.09, 58	3/29/09	PT
235	379-380, 486-487, 492-493, 375	3/29/09	PT

SEARCH NOTES		
Search Notes	Date	Examiner
East/West	3/29/09	PT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/P. N. T./ Primary Examiner.Art Unit 2618
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